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Counting Graphene Layers on Glass by Optical Reflection Microscopy HELGI SKULASON, PETER GASKELL, CHRIS RODENCHUK, THOMAS SZKOPEK, McGill University — Using optical reflection microscopy we can locate and count graphene layers on a bulk glass substrate. This is a reliable and low cost technique for graphene flake metrology. Optical reflection measurements are in agreement with the universal optical conductance of graphene. We present measurements of the optical conductivity of graphitic flakes showing a transition from few layer graphene to bulk graphite.

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